



2811

PATENT APPLICATION
ATTORNEY DOCKET NO. Q60098

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Yoko HORIGUCHI

Appln. No.: 09/615,705

Confirmation No.: Not Yet Assigned

Group Art Unit: 2811

Filed: July 13, 2000

Examiner: O. Nadav

For: SEMICONDUCTOR INTEGRATED CIRCUIT

AMENDMENT UNDER 37 C.F.R. § 1.111

Commissioner for Patents
Washington, D.C. 20231

Sir:

In response to the Office Action dated April 3, 2001, please amend the above-identified application as follows:

IN THE SPECIFICATION:

Page 8, please delete the first full paragraph and replace it with the following paragraph:

Thus, since the above described conventional techniques (Japanese Examined Patent Application, Second Publication No. Hei 7-24310, Japanese Patent (Granted) Publication No. 2650276, and Japanese Unexamined Patent Application, First Publication No. Hei 7-183457) do not relate to the CDM which is the breakdown model of the semiconductor integrated circuit of the present invention, the discharge path in the semiconductor integrated circuit of the present invention during electrostatic breakdown differs from those of the conventional integrated

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